



Specification of Automotive MLCC

• Supplier : Samsung electro-mechanics • Samsung P/N : CL21C820JB61PNC

• Product : Multi-layer Ceramic Capacitor • Description : CAP, 82pF, 50V, ±5%, C0G, 0805

• AEC-Q 200 Specified

A. Samsung Part Number

<u>CL</u> <u>21</u> <u>C</u> <u>820</u> <u>J</u> <u>B</u> <u>6</u> <u>1</u> <u>P</u> <u>N</u> <u>C</u> ① ② ③ ④ ⑤ ⑥ ⑦ ⑧ ⑨ ⑩ ⑪

1	Series	Samsung Multi-layer Ceramic Capacitor					
2	Size	0805 (inch code)	L: 2.0 :	± 0.1 mm	W:	1.25 ± 0.1	mm
3	Dielectric	COG	8 I	Inner electrode	Ni		
4	Capacitance	82 pF	-	Termination	Cu		
⑤	Capacitance	±5 %	1	Plating	Sn	100%	(Pb Free)
	tolerance		9 I	Product	Au	tomotive	
6	Rated Voltage	50 V	10	Grade code	Sta	andard	
7	Thickness	0.6 ± 0.1 mm	110	Packaging	Ca	rdboard Typ	e, 7" reel(4,000ea)

B. Reliability Test and Judgement condition

	Performance	Test condition			
High Temperature	Appearance : No abnormal exterior appearance	Unpowered, 1000hrs@T=150℃			
Exposure	Capacitance Change :	Measurement at 24±2hrs after test conclusion			
	within ±2.5% or ±0.25pF whichever is larger				
	Q: 1000 min				
	IR : More than 10,000№ or 500№×μF				
	Whichever is Smaller				
Temperature Cycling	Appearance : No abnormal exterior appearance	1000Cycles			
	Capacitance Change :	Measurement at 24±2hrs after test conclusion			
	within ±2.5% or ±0.25pF whichever is larger	1 cycle condition :			
	Q: 1000 min	-55+0/-3 °C (15±3min) -> Room Temp(1min.)			
	IR : More than 10,000MΩ or 500MΩ×μF	-> 125+3/-0 ℃(15±3min) -> Room Temp(1min.)			
	Whichever is Smaller				
Destructive Physical	No Defects or abnormalities	Per EIA 469			
Analysis					
Moisture Resistance	Appearance : No abnormal exterior appearance	10Cycles, t=24hrs/cycle			
	Capacitance Change :	Heat (25~65 °C) and humidity (80~98%), Unpowered			
	within ±2.5% or ±0.25pF whichever is larger	measurement at 24±2hrs after test conclusion			
	Q: 350 min				
	IR : More than 10,000MΩ or 500MΩ×μF				
	Whichever is Smaller				
Humidity Bias	Appearance : No abnormal exterior appearance	1000hrs 85°C/85%RH, Rated Voltate and 1.3~1.5V,			
	Capacitance Change :	Add 100kohm resistor			
	within ±2.5% or ±0.25pF whichever is larger	Measurement at 24±2hrs after test conclusion			
	Q: 200 min	The charge/discharge current is less than 50mA.			
	IR : More than 500MΩ or 25MΩ×μF				
	Whichever is Smaller				
High Temperature	Appearance : No abnormal exterior appearance	1000hrs @ TA=125 ℃, 200% Rated Voltage,			
Operating Life	Capacitance Change :	Measurement at 24±2hrs after test conclusion			
	within ±3.0% or ±0.3pF whichever is larger	The charge/discharge current is less than 50mA.			
	Q: 350 min				
	IR : More than 10,000№ or 500№×μF				
	Whichever is Smaller				

	Performance	Test condition				
External Visual	No abnormal exterior appearance	Visual inspection				
Physical Dimensions	Within the specified dimensions	Using The calipers				
Mechanical Shock	Appearance: No abnormal exterior appearance Capacitance Change: within ±2.5% or ±0.25pF whichever is larger Q, IR: initial spec.	Three shocks in each direction should be applied along 3 mutually perpendicular axes of the test specimen (18 shocks) Peakvalue Duration Wave Velocity 1,500G 0.5ms Half sine 4.7m/sec.				
Vibration	Appearance: No abnormal exterior appearance Capacitance Change: within ±2.5% or ±0.25pF whichever is larger Q, IR: initial spec.	5g's for 20min., 12cycles each of 3 orientations, Use 8"x5" PCB 0.031" Thick 7 secure points on one long side and 2 secure points at corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10~2000Hz.				
Resistance to	Appearance : No abnormal exterior appearance	Solder pot : 260±5 ℃, 10±1sec.				
Solder Heat	Capacitance Change : within ±2.5% or ±0.25pF whichever is larger Q, IR : initial spec.					
Thermal Shock	Appearance: No abnormal exterior appearance Capacitance Change: within ±2.5% or ±0.25pF whichever is larger Q, IR: initial spec.	-55 °C/+125 °C. Note: Number of cycles required-300, Maximum transfer time-20 sec, Dwell time-15min. Air-Air				
ESD	Appearance : No abnormal exterior appearance Capacitance Change : within ±2.5% or ±0.25pF whichever is larger Q, IR : initial spec.	AEC-Q200-002				
Solderability	95% of the terminations is to be soldered evenly and continuously	 a) Preheat at 155 °C for 4 hours, Immerse in solder for 5s at 245±5 °C b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5 °C c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5 °C solder: a solution ethanol and rosin 				
Electrical	Capacitance : Within specified tolerance	The Capacitance /Q should be measured at 25℃,				
Characterization	Q: 1000 max. IR(25℃): More than 100,000MΩ or 1,000MΩ×μF IR(125℃): More than10,000MΩ or 100MΩ×μF Whichever is Smaller Dielectric Strength	1Mb±10%, 0.5~5Vrms I.R. should be measured with a DC voltage not exceeding Rated Voltage @25℃, @125℃ for 60~120 sec. Dielectric Strength: 250% of the rated voltage for 1~5 seconds				
Board Flex	Appearance: No abnormal exterior appearance Capacitance Change: within ±5.0% or ±0.5pF whichever is larger	Bending to the limit (3mm) for 5 seconds				
Terminal	Appearance : No abnormal exterior appearance	18N, for 60±1 sec.				
Strength(SMD)	Capacitance Change : within ±2.5% or ±0.25pF whichever is larger					
Beam Load	Destruction value should not be exceed Chip Length < 2.5mm a) Chip Thickness > 0.5mm : 20N b) Chip Thickness ≤ 0.5mm : 8N	Beam speed 0.5±0.05mm/sec				
Temperature	COG					
characteristics	(From -55℃ to 125℃, Capacitance change should be within ±30PPM/℃)					

C. Recommended Soldering method :

^{*} For the more detail Specification, Please refer to the Samsung MLCC catalogue.